



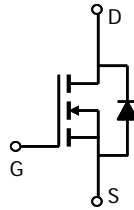
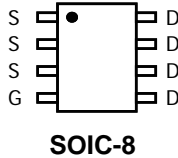
AO4430, AO4430L (Green Product)
N-Channel Enhancement Mode Field Effect Transistor

General Description

The AO4430 uses advanced trench technology to provide excellent $R_{DS(ON)}$, shoot-through immunity, body diode characteristics and ultra-low gate resistance. This device is ideally suited for use as a low side switch in Notebook CPU core power conversion. AO4430L (Green Product) is offered in a lead free package.

Features

- V_{DS} (V) = 30V
- I_D = 18A
- $R_{DS(ON)} < 5.5m\Omega$ ($V_{GS} = 10V$)
- $R_{DS(ON)} < 7.5m\Omega$ ($V_{GS} = 4.5V$)



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

| Parameter | Symbol | Maximum | Units |
|--|--------------------------------------|------------|------------|
| Drain-Source Voltage | V_{DS} | 30 | V |
| Gate-Source Voltage | V_{GS} | ± 20 | V |
| Continuous Drain Current ^A | $T_A=25^\circ C$ $T_A=70^\circ C$ | I_D | A |
| | | | |
| Pulsed Drain Current ^B | I_{DM} | 80 | |
| Power Dissipation | $T_A=25^\circ C$ $T_A=70^\circ C$ | P_D | W |
| | | | |
| | | 2.1 | |
| Junction and Storage Temperature Range | T_J, T_{STG} | -55 to 150 | $^\circ C$ |

Thermal Characteristics

| Parameter | Symbol | Typ | Max | Units |
|--|-----------------|-----|-----|--------------|
| Maximum Junction-to-Ambient ^A | $R_{\theta JA}$ | 31 | 40 | $^\circ C/W$ |
| $t \leq 10s$ | | | | |
| Maximum Junction-to-Ambient ^A | $R_{\theta JA}$ | 59 | 75 | $^\circ C/W$ |
| Steady-State | | | | |
| Maximum Junction-to-Lead ^C | $R_{\theta JL}$ | 16 | 24 | $^\circ C/W$ |

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|-----------------------------|---------------------------------------|---|-----|------|--------|------------------|
| STATIC PARAMETERS | | | | | | |
| BV_{DSS} | Drain-Source Breakdown Voltage | $I_D=250\mu\text{A}$, $V_{GS}=0\text{V}$ | 30 | | | V |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{DS}=24\text{V}$, $V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$ | | | 1 5 | μA |
| I_{GSS} | Gate-Body leakage current | $V_{DS}=0\text{V}$, $V_{GS}=\pm 20\text{V}$ | | | 100 | nA |
| $V_{GS(th)}$ | Gate Threshold Voltage | $V_{DS}=V_{GS}$, $I_D=250\mu\text{A}$ | 1 | 1.8 | 2.5 | V |
| $I_{D(ON)}$ | On state drain current | $V_{GS}=4.5\text{V}$, $V_{DS}=5\text{V}$ | 80 | | | A |
| $R_{DS(ON)}$ | Static Drain-Source On-Resistance | $V_{GS}=10\text{V}$, $I_D=18\text{A}$ $T_J=125^\circ\text{C}$ | | 4.7 | 5.5 | $\text{m}\Omega$ |
| | | $V_{GS}=4.5\text{V}$, $I_D=15\text{A}$ | | 6.2 | 7.5 | $\text{m}\Omega$ |
| g_{FS} | Forward Transconductance | $V_{DS}=5\text{V}$, $I_D=18\text{A}$ | | 82 | | S |
| V_{SD} | Diode Forward Voltage | $I_S=1\text{A}$, $V_{GS}=0\text{V}$ | | 0.7 | 1 | V |
| I_S | Maximum Body-Diode Continuous Current | | | | 4.5 | A |
| DYNAMIC PARAMETERS | | | | | | |
| C_{iss} | Input Capacitance | $V_{GS}=0\text{V}$, $V_{DS}=15\text{V}$, $f=1\text{MHz}$ | | 6060 | | pF |
| C_{oss} | Output Capacitance | | | 638 | | pF |
| C_{riss} | Reverse Transfer Capacitance | | | 355 | | pF |
| R_g | Gate resistance | $V_{GS}=0\text{V}$, $V_{DS}=0\text{V}$, $f=1\text{MHz}$ | | 0.45 | | Ω |
| SWITCHING PARAMETERS | | | | | | |
| $Q_g(10\text{V})$ | Total Gate Charge | $V_{GS}=10\text{V}$, $V_{DS}=15\text{V}$, $I_D=18\text{A}$ | | 103 | | nC |
| $Q_g(4.5\text{V})$ | Total Gate Charge | | | 48 | | nC |
| Q_{gs} | Gate Source Charge | | | 18 | | nC |
| Q_{gd} | Gate Drain Charge | | | 15 | | nC |
| $t_{D(on)}$ | Turn-On Delay Time | $V_{GS}=10\text{V}$, $V_{DS}=15\text{V}$, $R_L=0.83\Omega$, $R_{GEN}=3\Omega$ | | 12 | | ns |
| t_r | Turn-On Rise Time | | | 8 | | ns |
| $t_{D(off)}$ | Turn-Off Delay Time | | | 51.5 | | ns |
| t_f | Turn-Off Fall Time | | | 8.8 | | ns |
| t_{rr} | Body Diode Reverse Recovery Time | $I_F=18\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$ | | 33.5 | | ns |
| Q_{rr} | Body Diode Reverse Recovery Charge | $I_F=18\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$ | | 22 | | nC |

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1in^2 FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any a given application depends on the user's specific board design. The current rating is based on the $\leq 10\text{s}$ thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to lead $R_{\theta JL}$ and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using $80\mu\text{s}$ pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1in^2 FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

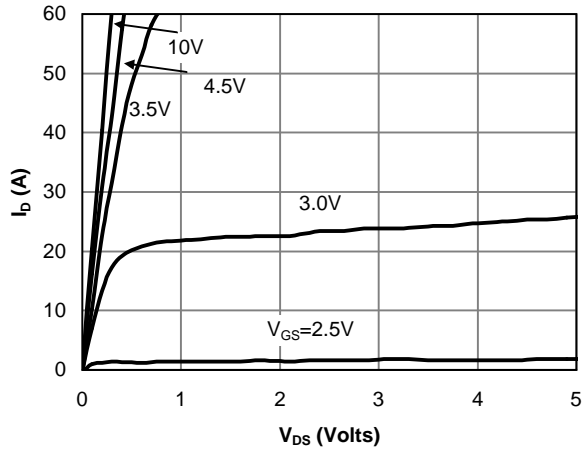


Fig 1: On-Region Characteristics

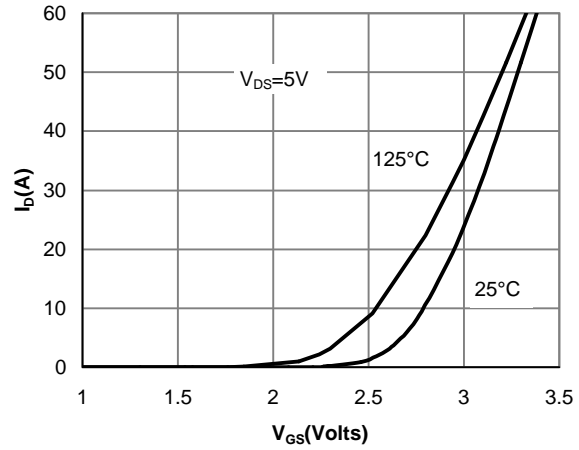


Figure 2: Transfer Characteristics

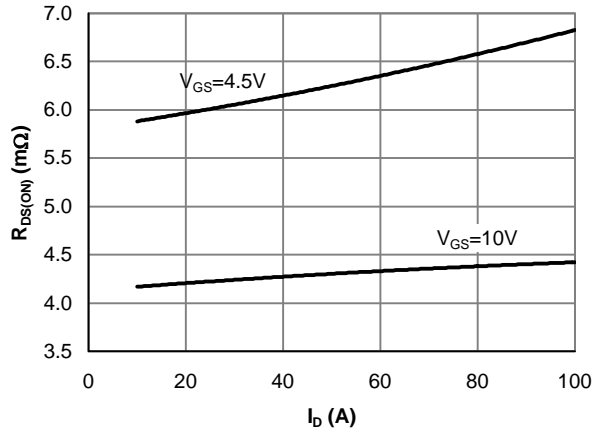


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

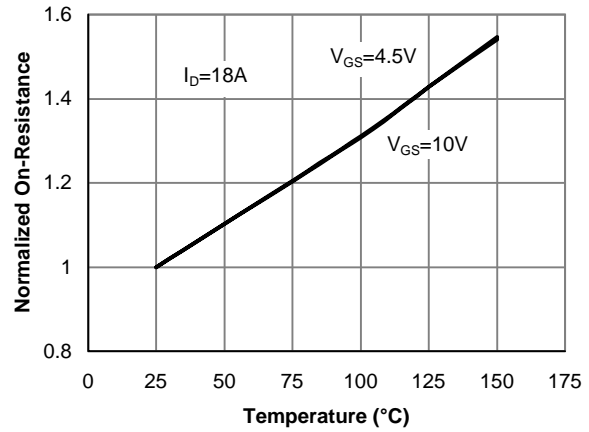


Figure 4: On-Resistance vs. Junction Temperature

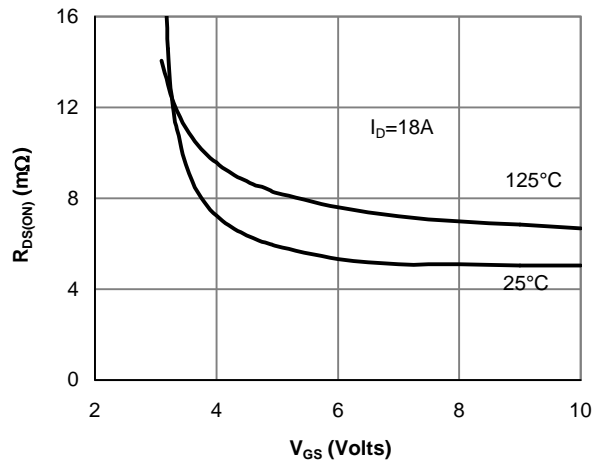


Figure 5: On-Resistance vs. Gate-Source Voltage

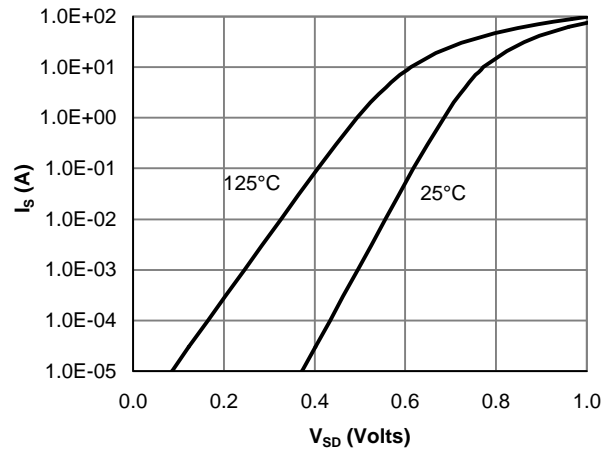


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

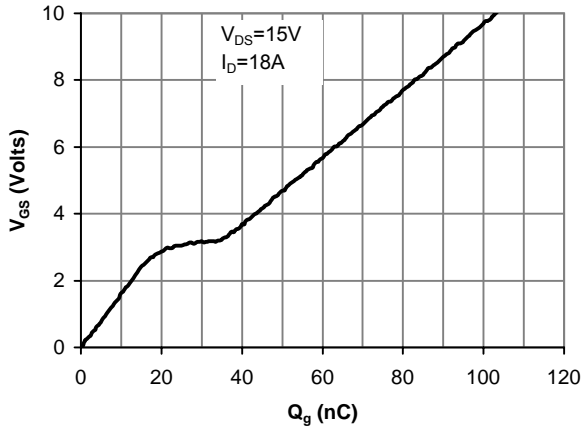


Figure 7: Gate-Charge Characteristics

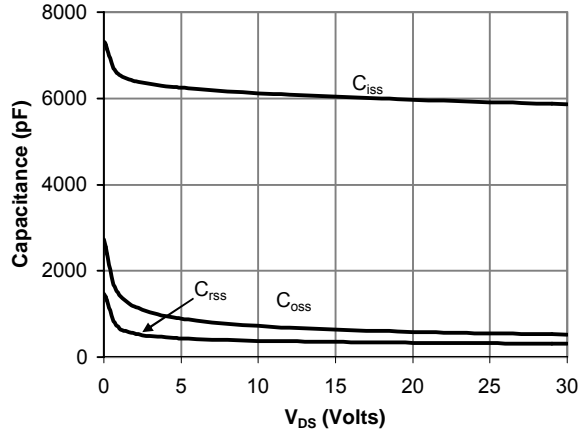


Figure 8: Capacitance Characteristics

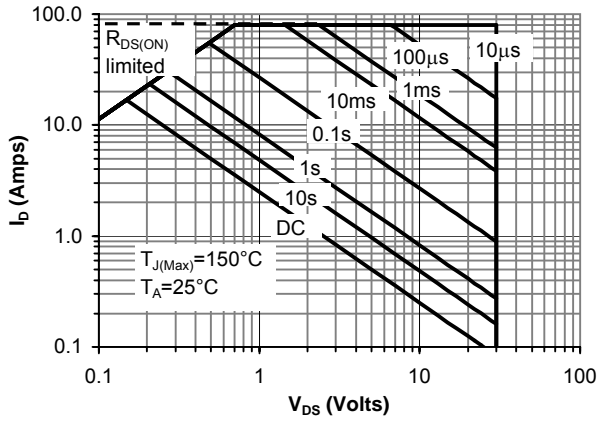


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

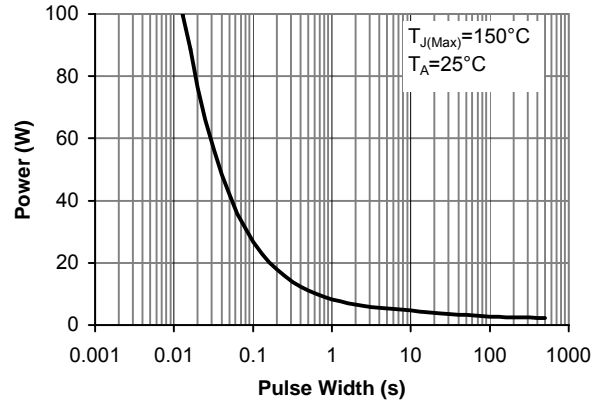


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

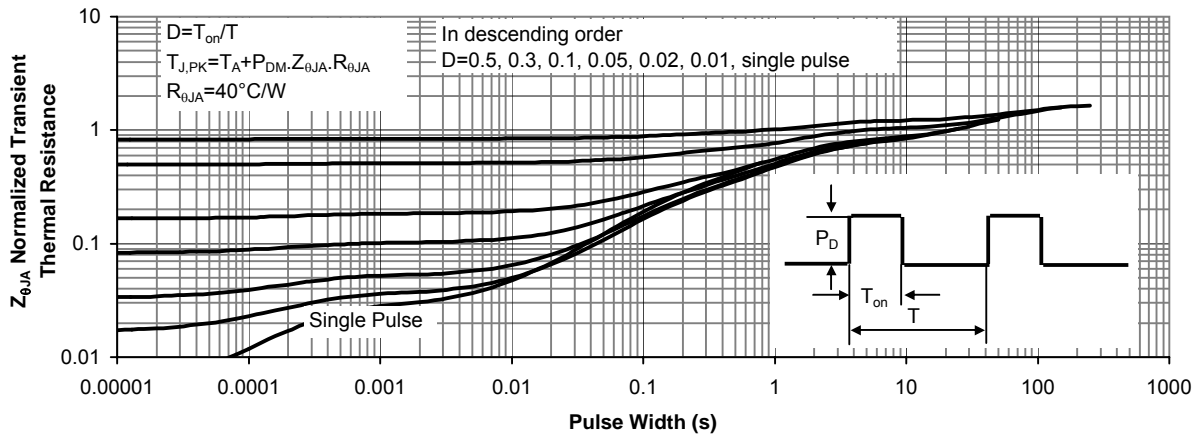


Figure 11: Normalized Maximum Transient Thermal Impedance